

Please replace the Abstract on page 12 with the following amended abstract:

STUCK-AT SCAN CHAIN DIAGNOSTIC METHOD

ABSTRACT

While data cannot be transmitted down a scan chain through a stuck-at fault location, data in properly operating latches downstream of the stuck-at fault location can be shifted down the chain. By varying [[an]] operating parameter, such as power supply and reference voltages, clock timing patterns, temperature and timing sequences, one or more latches down the SRL chain from the stuck-at fault location may be triggered to change state from the stuck-at fault value. The SRL chain is then operated to shift data out the output of the SRL chain. The output is monitored and any change in value from the stuck-at state is noted as identifying all good latch positions to end of the chain. The process is repeated; varying each of the selected operating parameters [[with]] until the latch position following the stuck-at fault latch is identified.